



ALPHA & OMEGA
SEMICONDUCTOR, LTD

AO3409

P-Channel Enhancement Mode Field Effect Transistor



General Description

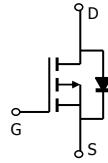
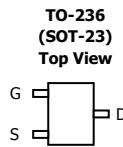
The AO3409/L uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. This device is suitable for use as a load switch or in PWM applications. AO3409 and AO3409L are electrically identical.

-RoHS Compliant

-AO3409L is Halogen Free

Features

V_{DS} (V) = -30V
 I_D = -2.6 A (V_{GS} = -10V)
 $R_{DS(ON)} < 130\text{m}\Omega$ (V_{GS} = -10V)
 $R_{DS(ON)} < 200\text{m}\Omega$ (V_{GS} = -4.5V)



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^A	I_D	-2.6	A
$T_A=70^\circ\text{C}$		-2.2	
Pulsed Drain Current ^B	I_{DM}	-20	
Power Dissipation ^A	P_D	1.4	W
$T_A=70^\circ\text{C}$		1	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	70	90	°C/W
Steady-State		100	125	°C/W
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	63	80	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		-1	-5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.4	-1.9	-3	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-5			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-2.6\text{A}$ $T_J=125^\circ\text{C}$	97	130		$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$	135	150	200	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=2.5\text{A}$	3	3.8		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.82	-1	V
I_S	Maximum Body-Diode Continuous Current				-2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		302	370	pF
C_{oss}	Output Capacitance			50.3		pF
C_{rss}	Reverse Transfer Capacitance			37.8	53	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	6	12	18	Ω
SWITCHING PARAMETERS						
$Q_g(10)$	Total Gate Charge(10V)	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-2.6\text{A}$		6.8	9	nC
$Q_g(4.5)$	Total Gate Charge(4.5V)			2.4	3.1	nC
Q_{gs}	Gate Source Charge			1.6		nC
Q_{gd}	Gate Drain Charge			0.95		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=5.8\Omega, R_{\text{GEN}}=3\Omega$		7.5		ns
t_r	Turn-On Rise Time			3.2		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			17		ns
t_f	Turn-Off Fall Time			6.8		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-2.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		16.8	22	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-2.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		10		nC

A: The value of R_{QA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{QA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using <300 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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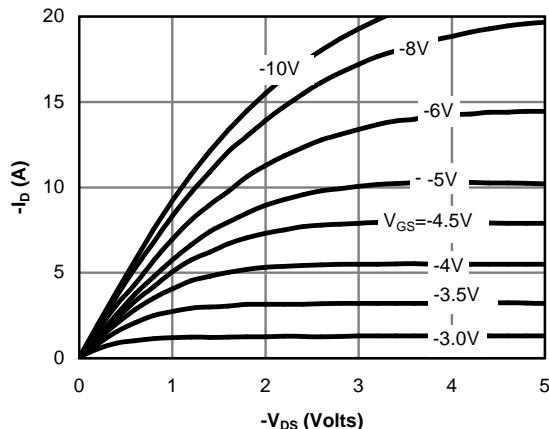
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics

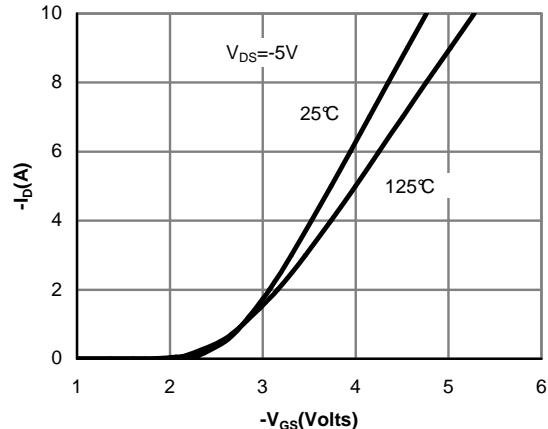


Figure 2: Transfer Characteristics

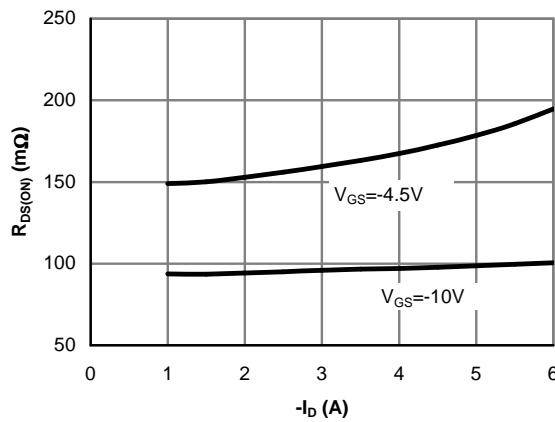


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

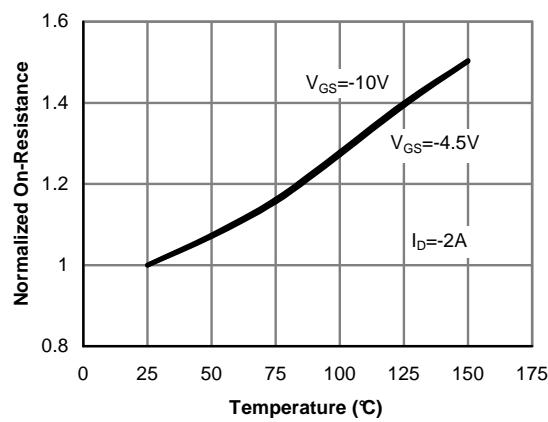


Figure 4: On-Resistance vs. Junction Temperature

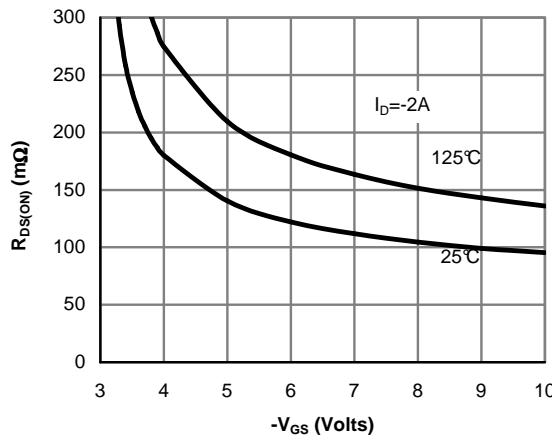


Figure 5: On-Resistance vs. Gate-Source Voltage

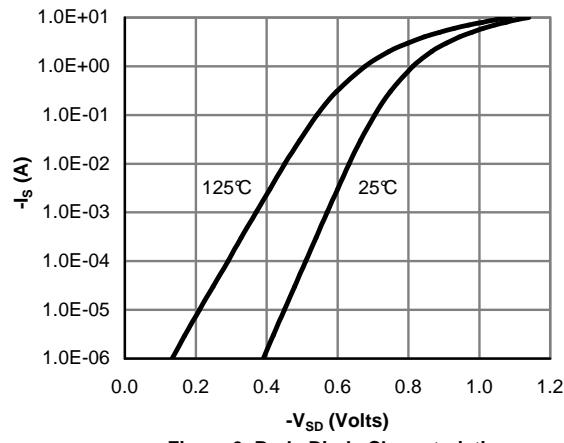


Figure 6: Body-Diode Characteristics

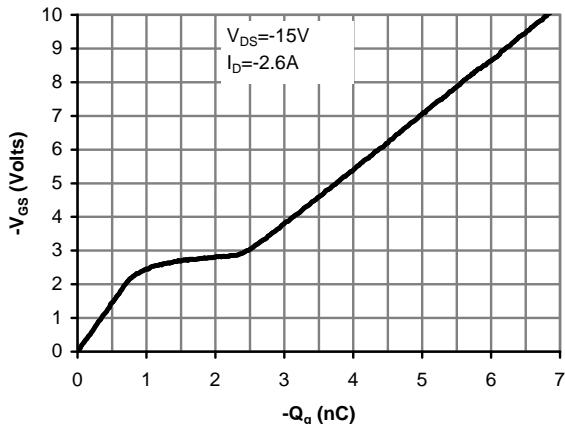
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 7: Gate-Charge Characteristics

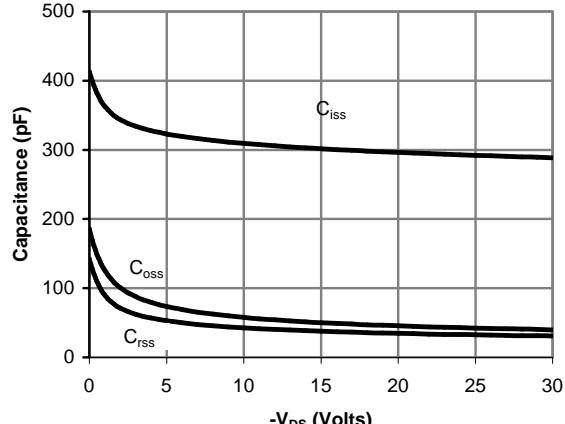


Figure 8: Capacitance Characteristics

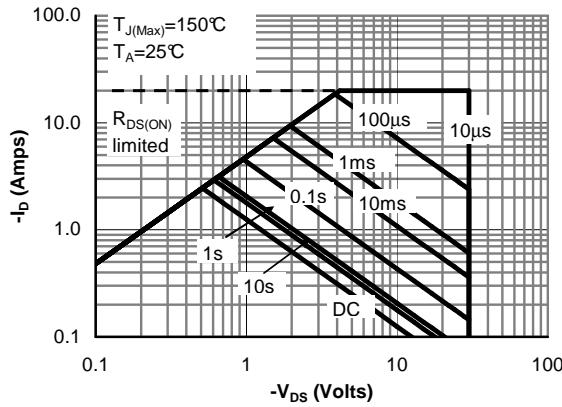


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

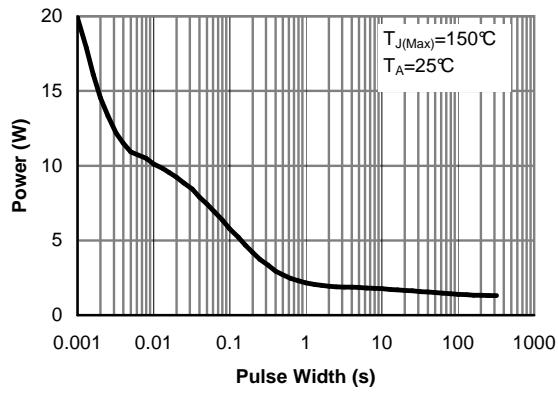


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

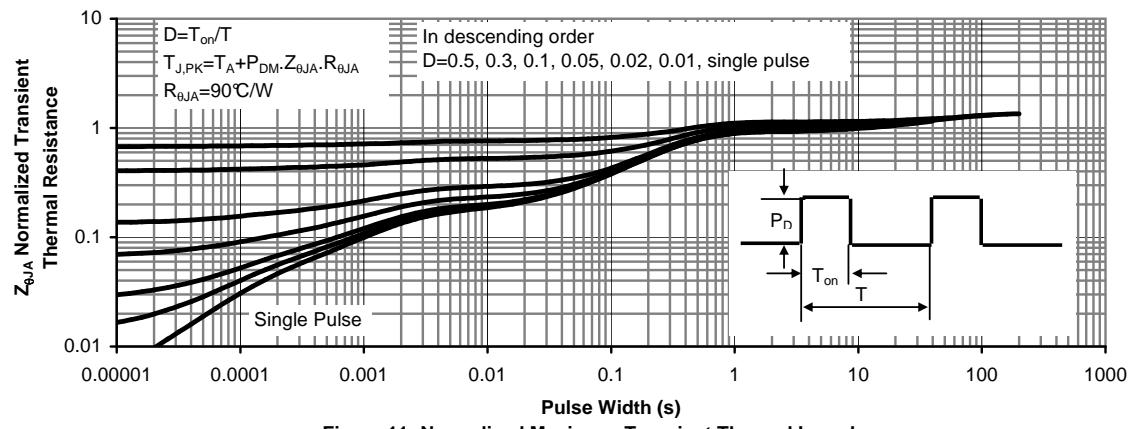


Figure 11: Normalized Maximum Transient Thermal Impedance